

Designation: D5861 - 07 (Reapproved 2017)

Standard Guide for Significance of Particle Size Measurements of Coating Powders¹

This standard is issued under the fixed designation D5861; the number immediately following the designation indicates the year of original adoption or, in the case of revision, the year of last revision. A number in parentheses indicates the year of last reapproval. A superscript epsilon (ε) indicates an editorial change since the last revision or reapproval.

1. Scope

- 1.1 This guide covers the significance of referencing the techniques used whenever specifying the particle size distribution of a coating powder.
- 1.2 This international standard was developed in accordance with internationally recognized principles on standardization established in the Decision on Principles for the Development of International Standards, Guides and Recommendations issued by the World Trade Organization Technical Barriers to Trade (TBT) Committee.

2. Referenced Documents

- 2.1 ASTM Standards:²
- D1921 Test Methods for Particle Size (Sieve Analysis) of Plastic Materials
- D3451 Guide for Testing Coating Powders and Powder Coatings

3. Terminology

- 3.1 Definitions:
- 3.1.1 *coating powders, n*—these are finely divided particles of organic polymer that generally contain pigments, fillers, and additives and that remain finely divided during storage under suitable conditions.
- 3.1.2 *powder coatings, n*—these are coatings that are protective, decorative, or both; and that are formed by the application of a coating powder to a substrate and fused into continuous films by the application of heat or radiant energy.

4. Significance and Use

4.1 This guide describes the need to specify the measuring technique used whenever quoting the particle size distribution of a coating powder.

4.2 This guide is for use by manufacturers of coating powders and by specifiers for process control and product acceptance.

5. Particle Size of Coating Powders

- 5.1 The size of the particles comprising a coating powder plays a critical role in the fluidization, application, and reclamation of the powder, and in the final appearance of the coated part. Coating powders are comprised of particles of widely differing sizes, from as low as about 1 µm to as high as about 150 µm. Collectively, the individual particles form a size distribution, defined by the percentages of particles present of a given size or within a given size range. There are generally few particles at the low and high ends of the distribution, the majority being in the 25 to 65-µm range. The distribution can be described by an actual plot of the particle size distribution, or by numerical attributes of the distribution, such as the calculated values of its mean, median, mode, and span. The mean represents the average particle size (the sum of all the particle sizes divided by the number of particles). The median represents a size such that half the particles are larger than it and half the particles are smaller than it. The mode represents the most frequently occurring particle size. For all coating powders these three figures are numerically different. The span is an indication of the width of the particle size distribution. Referring to Table A1.1, the span is calculated by subtracting the d10 from the d90 and then dividing by the d50 or median particle size.
- 5.2 The particle size distribution is generally chosen by the coating powder manufacturer from knowledge of the application technique, the required cured film thickness, surface appearance, and performance. Once the desired particle size distribution has been selected, it needs to be monitored to ensure consistency from batch to batch and, indeed, within each batch. Occasionally the coating powder applicator may specify the particle size from knowledge of the specific application equipment or customer requirements, or both.
- 5.3 It is important for all involved to understand that the numerical data comprising a particle size distribution are significantly dependent on the technique used to obtain them. It is, therefore, of little use to quote or specify a particle size distribution, and even less a single particle size, without also

¹ This guide is under the jurisdiction of ASTM Committee D01 on Paint and Related Coatings, Materials, and Applications and is the direct responsibility of Subcommittee D01.51 on Powder Coatings.

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² For referenced ASTM standards, visit the ASTM website, www.astm.org, or contact ASTM Customer Service at service@astm.org. For *Annual Book of ASTM Standards* volume information, refer to the standard's Document Summary page on the ASTM website.



defining the technique used to obtain that measurement, or, if a single size, whether it is, for example, the mean, median or modal value.

6. Measurement of Particle Size

- 6.1 There are a wide variety of instruments currently available for measuring the particle size distributions of coating powders. Actual sieving, such as described in Test Methods D1921, where the percentage weight of coating powder retained on sieves of known mesh size is measured, is relatively inexpensive and direct. It is, however, significantly slower than indirect measurement techniques, such as laser scattering and electrolytic conductivity, such as described in Guide D3451. With indirect measurement techniques, a secondary effect, induced by the presence of the coating powder particles, is measured, such as changes in light scattering or in the conductivity of an electrolyte. These effects are analyzed using a specific theoretical algorithm, unique to the measurement technique, and the particle size distribution calculated that would cause the measured changes. Various other statistical data on the distributions, such as the mean, the median, the mode, and the span are also often automatically calculated.
- 6.2 Secondary measurement techniques make assumptions such as the measured particles being spherical, and do not acknowledge the fractured, randomized shapes the particles actually possess. Others require the preparation of a suspension of the particles in a liquid, which could alter the physical state of particle agglomerates present in the dry state. Even the required processing for dry powder measurement techniques could mechanically break up larger particles or agglomerates into smaller ones, or both.
- 6.3 Thus not only can the theoretical algorithms for the measuring techniques be quite different, but each measurement technique can cause the particle size distribution to change during sample preparation or the measurement process itself, or both. This simply serves to emphasize that once a measurement technique has been selected, there is still need for consistency in all aspects of its operation.

7. Effect of Using Different Measurement Techniques

7.1 To illustrate the numerical differences in measured particle size that can be found when different measurement techniques are used, the same coating powder was provided to a number of participants, who measured the particle size of the sample, usually in triplicate, using their own preferred tech-

nique. Participants included coating powder manufacturers, raw material suppliers to the powder coating market, and manufacturers of particle size measuring equipment.

- 7.2 The data obtained can be found in Annex A1 and Annex A2. They have been transposed into two respective standard formats for ease of comparison. Where possible, additional numerical data were extracted from the original plots of particle size distribution. In these instances, such figures are enclosed in parentheses in Annex A1 (see Figs. A1.1-A1.14). Some of the original plots of particle size distribution were replotted for clarity, with a consistent ordinate and abscissa, of "percentage of particles in a given range" and "log (particle size in µm)" respectively. These standardized distributions constitute Figs. A1.1-A1.14.
- 7.3 It can be seen that there are distinct differences between the data acquired by different techniques, and by the same technique when the machine manufacturer or model is changed. There are even differences when instruments with the same model number are used in different laboratories.
- 7.4 It must be emphasized that these data are not presented in order to recommend one measurement technique over another, or one participating piece of equipment over another nonparticipating piece of equipment, but rather to clearly illustrate the *necessity of defining how a size measurement is obtained* when quoting any numerical value regarding particle size.

8. Measurement Techniques Used

- 8.1 Agitated Sieving, Dry Sampling
- 8.2 Electrolyte Conductivity, Wet Sampling
- 8.3 Laser Scattering, Dry Sampling
- 8.4 Laser Scattering, Wet Sampling
- 8.5 Sedimentation/X-Ray Absorption, Wet Sampling
- 8.6 Mercury Porosimetry, Dry Sampling

Note 1—Mercury porosimetry requires the use of mercury. The proper safety precautions should be taken when handling mercury as a hazardous element.

8.7 Note that some of the instruments were used independently of each other, and by more than one participant.

9. Keywords

9.1 coating powder; electroconductivity; laser scattering; mercury porosimetry; particle size analysis; powder coating; sedimentation; sieve analysis; X-ray

ANNEXES

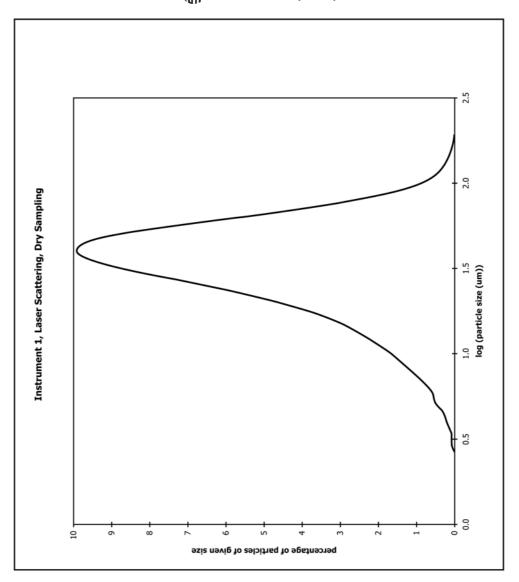
(Mandatory Information)

A1. DATA AS ILLUSTRATED IN Table A1.1

TABLE A1.1 Particle Size Data from Secondary Measurement Techniques^A

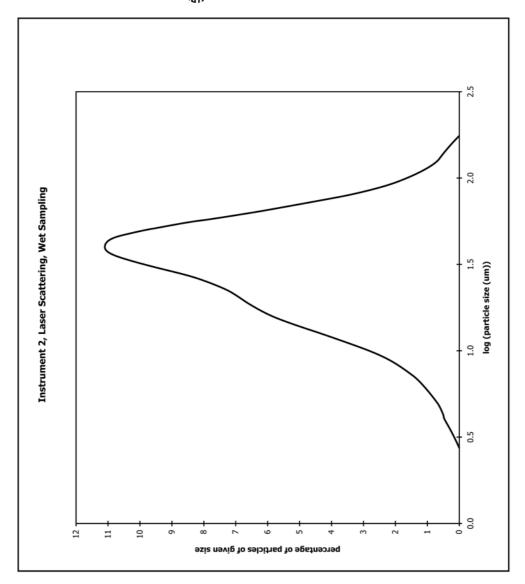
Instrumen	t				Per	cent of P	articles L	ess Than I	Micron Siz	ze in Body	y of Table				Mean,	Median,	Mode,
Number	Method -	5	10	20	25	30	40	50	60	70	75	80	90	95	(µm)	(µm)	(µm)
1	Laser		11.8			23.0		32.2		42.5			60.4			32.2	
	scattering		11.3			22.4		31.9		42.3			59.6			31.9	
	(dry)		11.6			22.7		32.0		42.3			59.3			32.0	
2	Laser		10.6					29.7					61.1		33.5	29.7	
	scattering		11.0					30.9					64.6		35.1	30.9	
	(wet)		10.8					30.2					62.2		34.2	30.2	
3	Laser		8.4					28.7					58.8		34.8	28.7	36.9
	scattering		8.5					28.6					58.8		35.2	28.6	36.8
	(dry)		8.4					28.6					58.9		35.0	28.6	37.0
4	Laser		8.3					26.1					51.9			26.1	
	scattering		8.4					26.2					52.4			26.2	
	(dry)		8.4					26.1					52.2			26.1	
5	Laser		12.6					33.3					63.2		36.1	33.3	
Ü	scattering		12.8					33.2					63.3		36.1	33.2	
	(dry)		12.7					33.0					63.8		36.1	33.0	
6	Laser		12.7					00.0					00.0		46.1	00.0	(37.0)
O	scattering														46.1		(37.0)
	(wet)														46.0		(37.0)
7	Laser		9.6					30.3					60.4		32.9	30.3	(37.0)
1	scattering		7.6					29.2					59.8		31.7	29.2	
	(dry)		9.8					30.5					60.0		32.9	30.5	
8	Laser		12.4					32.7					62.1		35.6	32.7	
0	scattering		12.4					32.1					60.9		35.0	32.1	
	•		12.4					32.5					61.2		35.6	32.5	
9	(dry)	6.8	10.4	15.9		21.1	26.0	30.6	35.3	40.4		46.6	55.7	64.5	33.0	30.6	(00.0)
9	Laser		9.8	14.8		21.1 19.4	26.0 24.0	28.4	35.3 32.9	38.1		46.6 44.4	55.7 54.5	64.5		28.4	(36.2)
	scattering	6.4	9.8	14.8		19.4	24.0	20.4	32.9	36.1		44.4	54.5	04.5		28.4	(31.0)
40	(dry)		44.5					05.7					740		040	05.7	00.0
10	Electrolyte		14.5					35.7 23.6					74.0		34.0	35.7	38.9
	conductivity		11.0										43.3		22.7	23.6	26.3
- 44	(wet)		11.2					26.2					58.6		25.7	26.2	27.4
11	Electrolyte		7.6					18.1					38.4		17.7	18.1	19.4
	conductivity		6.4					13.7					29.4		13.8	13.7	14.3
40	(wet)		6.0		47.0			12.3			447		24.6		12.4	12.3	12.8
12	Laser		9.6		17.8			30.3			44.7		58.0		32.2	30.3	38.9
	scattering		9.8		18.4			31.3			45.8		60.3		33.6	31.3	38.9
	(dry)		9.9		18.5			31.4			45.8		59.7		33.3	31.4	38.9
13	Sedimentation	1	(11)					(25)					(42)			(25)	
	(X-ray		(10)					25.1					(46)			25.1	27.2
	absorption)		(10)					25.0					(46)			25.0	27.1
14	Mercury		(9.0)					24.8					(130)			24.8	24.4
	porosimetry ^B		(9.0)					22.4					(90)			22.4	20.3
			(9.0)					24.2					(100)			24.2	24.5
15	Laser	(4.0)	(6.2)	(10.4)	(12.5)	(14.6)	(19.0)	(23.5)	(28.9)	(34.3)	(37.8)	(41.7)	(53.0)	(63.0)		(23.5)	35.8
	scattering	(3.8)	(6.2)	(10.3)	(12.3)	(14.4)	(18.6)	(23.4)	(28.5)	(34.1)	(37.4)	(41.2)	(52.1)	(62.4)		(23.4)	35.7
	(dry)	(3.8)	(6.2)	(10.2)	(12.2)	(14.2)	(18.5)	(23.2)	(28.4)	(34.0)	(37.4)	(41.0)	(52.0)	(62.2)		(23.2)	35.6

A All figures in the body of the table are in microns and are volume based except for instrument No. 13 data which are weight based. Figures in () were not provided explicitly, and so have been estimated from the original data/graphs. $^{\mathcal{B}}$ Data processed after Mayer & Stowe.



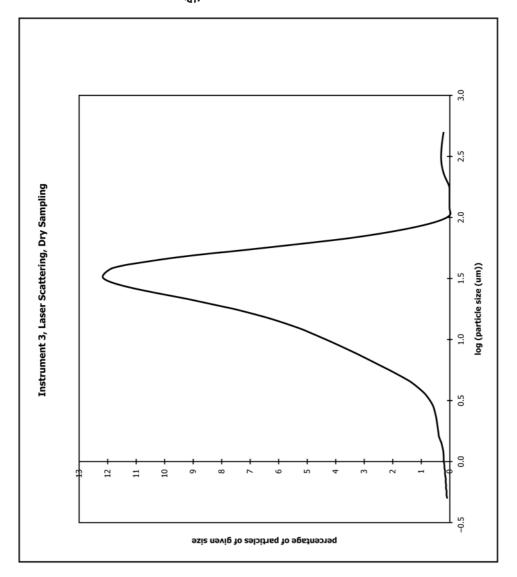
Instrument	1:	
Particle Size (11m)	Log (size)	Percentage of particles of given size
2.6	0.4150	0.
3	0.4771	0.1
3.4	0.5315	0.1
3.9	0.5911	0.2
4.5	0.6532	0.3
5.1	0.7076	0.5
5.9	0.7709	9.0
6.7	0.8261	8.0
7.7	0.8865	1.1
8.8	0.9445	1.4
10.1	1.0043	1.7
11.6	1.0645	2.1
13.2	1.1206	2.5
15.2	1.1818	3.0
17.4	1.2405	3.7
19.9	1.2989	4.6
22.8	1.3579	5.7
26.1	1.4166	7.0
29.9	1.4757	8.3
34.3	1.5353	9.4
39.2	1.5933	6.6
44.9	1.6522	9.6
51.5	1.7118	8.4
29	1.7709	9.9
67.5	1.8293	4.6
77.3	1.8882	2.9
9.88	1.9474	1.6
101.4	2.0060	8.0
116.2	2:0652	9.4
133.1	2.1242	0.2
152.4		0.1
174.6	2.2420	0.0

FIG. A1.1 Instrument 1, Laser Scattering, Dry Sampling



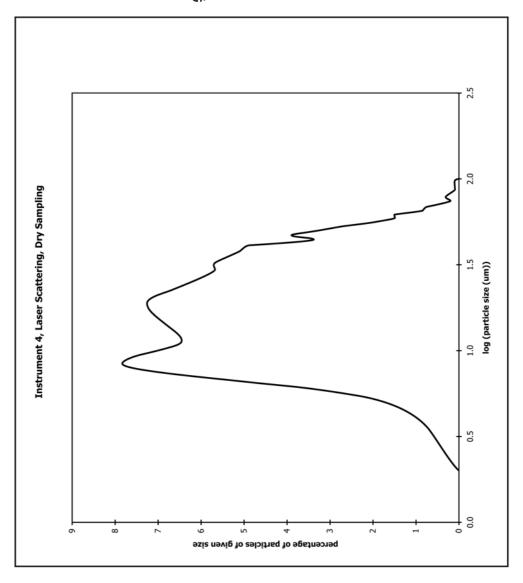
	Percentage of particles of given size	0.0	0.2	0.4	9.0	0.9	1.2	1.7	2.4	3.4	4.6	5.8	9.9	7.2	8.2	9.7	11.0	10.9	9.2	6.7	4.3	2.5	1.4	0.7	70
2:	Log (size)	0.4393	0.5145	0.5899	0.6646	0.7404	0.8156	0.8910	0.9661	1.0414	1.1173	1.1931	1.2672	1.3424	1.4183	1.4928	1.5682	1.6435	1.7185	1.7938	1.8692	1.9445	2.0199	2.0952	2.1703
Instrument	Particle Size (um)	2.8	3.3	3.9	4.6	5.5	6.5	7.8	9.3	11.0	13.1	15.6	18.5	22.0	26.2	31.1	37.0	44.0	52.3	62.2	74.0	88.0	104.7	124.5	148.0

FIG. A1.2 Instrument 2, Laser Scattering, Wet Sampling



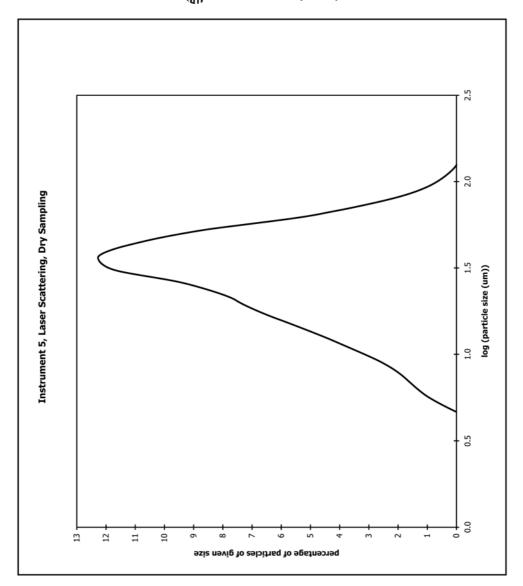
Instrument	3:	
Particle	Log (size)	entage of
Size (um)		particles of given size
0.5	-0.3010	0.1
1.3	0.1206	0.3
1.6	0.2041	0.4
2.0	0.2900	0.4
2.4	0.3766	0.5
2.9	0.4624	9.0
3.5	0.5478	0.8
4.3	0.6335	1.3
5.2	0.7193	1.9
6.4	0.8055	2.6
7.8	0.8910	3.3
9.5	0.9768	4.1
11.6	1.0626	5.0
14.1	1.1486	6.0
17.2	1.2343	7.4
20.9	1.3201	9.1
25.5	1.4059	11.0
31.0	1.4915	12.2
37.8	1.5774	11.8
46.0	1.6630	9.6
56.1	1.7489	6.3
68.3	1.8346	3.3
83.3	1.9204	1.1
101.4		0.0
123.6	2.0920	0.0
150.6	2.1777	0.0
183.4	2.2635	0.0
223.5	2.3493	0.2
272.3	2.4351	0.2
331.8	2.5208	0.3
4.		0.2
492.5	2.6924	0.2

FIG. A1.3 Instrument 3, Laser Scattering, Dry Sampling



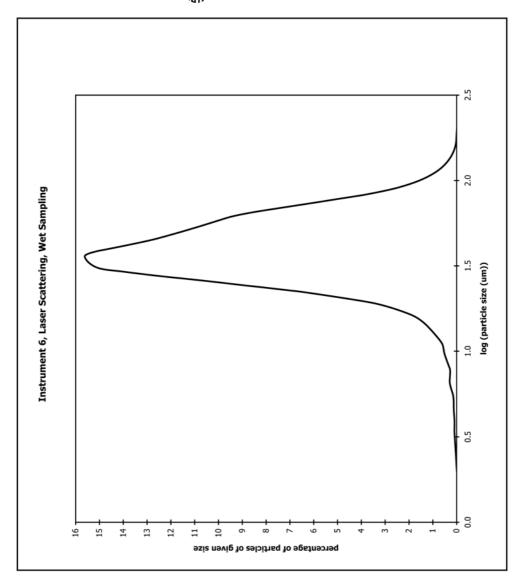
Ľ١		
Particle Size (um)	Log (size)	Percentage of particles of given size
2.0	0.3010	0
2.0	0.6990	1.7
8.0	0.9031	7.7
11.0	1.0414	6.5
14.0	1.1461	8.9
17.0	1.2304	7.2
20.0	1.3010	7.2
23.0	1.3617	9.9
26.0	1.4150	6.1
29.0	1.4624	5.7
32.0	1.5051	5.7
35.0	1.5441	5.4
38.0	1.5798	5.1
41.0	1.6128	4.9
44.0	1.6435	3.4
47.0	1.6721	3.9
20.0	1.6990	3.3
53.0	1.7243	2.7
26.0	1.7482	2
29.0	1.7709	1.5
62.0	1.7924	1.5
65.0	1.8129	6.0
0.89	1.8325	8.0
71.0	1.8513	0.5
74.0	1.8692	0.2
77.0	1.8865	0.3
80.0	1.9031	0.3
83.0	1.9191	0.2
86.0	1.9345	0.1
89.0	1.9494	0.1
92.0	1.9638	0.1
92.0	1.9777	0.1
0.86	1.9912	0.1
101.0	2.0043	0
104.0	2.0170	0
107.0	029	0
110.0	2.0414	C

FIG. A1.4 Instrument 4, Laser Scattering, Dry Sampling



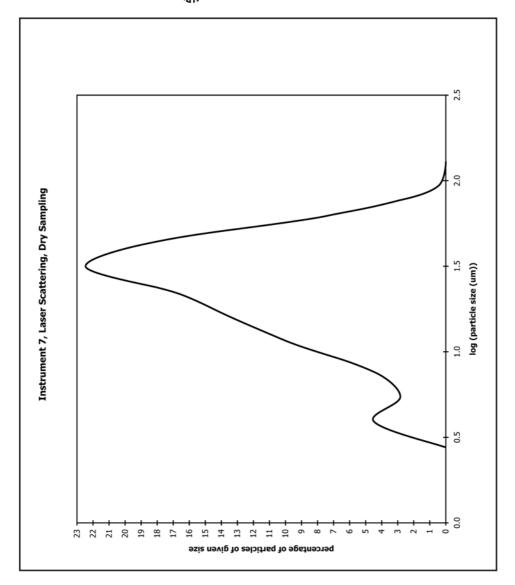
Instrument	5:	
Particle	Log (size)	Percentage of
Size (nm)		particles of given size
4.6	0.6646	0.0
5.5	0.7404	6.0
6.5	0.8156	1.5
7.8	0.8910	2.0
9.3	0.9661	2.7
11.0	1.0414	3.7
13.1	1.1166	4.7
15.6	1.1920	5.9
18.5	1.2672	7.1
22.0	1.3424	8.0
29.5	1.4176	9.5
31.1	1.4929	11.8
37.0	1.5682	12.3
44.0	1.6435	11.0
52.3	1.7188	8.7
62.2	1.7940	5.4
74.0	1.8692	3.0
88.0	1.9445	1.4
104.7	2.0197	0.5
124.5	2.0950	0.0

FIG. A1.5 Instrument 5, Laser Scattering, Dry Sampling



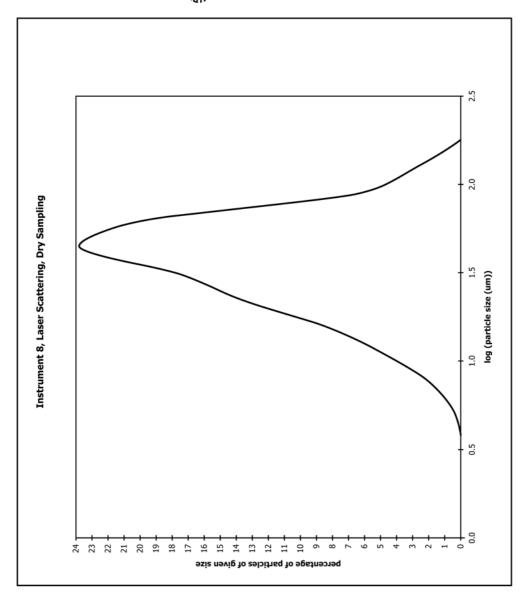
Instrument	9:	
Particle	Log (size)	Percentage of
Size (um)		particles of given size
1.9	0.2788	0.0
2.3	0.3617	0.0
2.8	0.4472	0.0
3.3	0.5185	0.1
3.9	0.5911	0.1
4.6	0.6628	0.1
5.5	0.7404	0.2
6.5	0.8129	0.3
7.8	0.8921	0.3
9.5	0.9638	0.5
11.0	1.0414	9.0
13.0	1.1139	1.0
16.0	1.2041	1.8
19.0	1.2788	3.4
22.0	1.3424	6.4
26.0	1.4150	10.7
31.0	1.4914	15.1
37.0	1.5682	15.6
44.0	1.6435	13.1
53.0	1.7243	11.0
63.0	1.7993	9.1
75.0	1.8751	5.7
88.0	1.9445	2.9
105.0	2.0212	1.2
125.0		0.5
149.0	2.1732	0.1
177.0		0.0
210.0	2.3222	0.0
250.0	2.3979	0.0
298.0	4.	0.0
354.0	2.5490	0.0

FIG. A1.6 Instrument 6, Laser Scattering, Wet Sampling



Instrument 7:	7:	
Particle	Log (size)	Percentage of
Size (nm)		particles of given size
2.8	0.4393	0.0
3.9	0.5899	4.5
5.5	0.7404	2.9
7.8	0.8910	4.7
11.0	1.0414	9.4
15.6	1.1920	13.2
22.0	1.3424	16.8
31.1	1.4929	22.5
44.0	1.6435	17.9
62.2	1.7940	7.3
88.0	1.9445	0.8
124.5	2.0950	0.0

FIG. A1.7 Instrument 7, Laser Scattering, Dry Sampling



Instrument 8:	8:	
Particle	Log (size)	Percentage of
Size (nm)		particles of given size
3.9	0.5899	0.0
5.5	0.7404	9.0
7.8	0.8910	2.2
11.0	1.0414	4.8
15.6	1.1920	8.4
22.0	1.3424	13.6
31.1	1.4929	17.7
44.0	1.6435	23.8
62.2	1.7940	19.7
88.0	1.9445	6.5
124.5	2.0950	2.8
176.0	2.2455	0.0

FIG. A1.8 Instrument 8, Laser Scattering, Dry Sampling

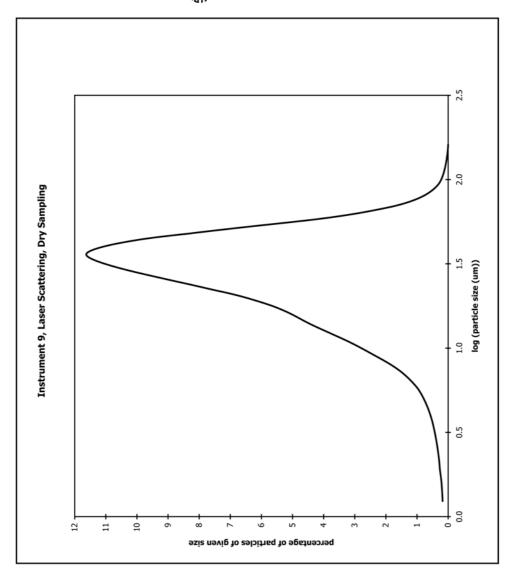
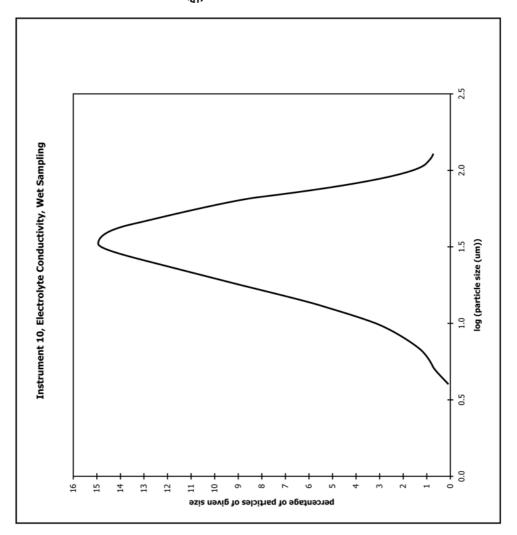
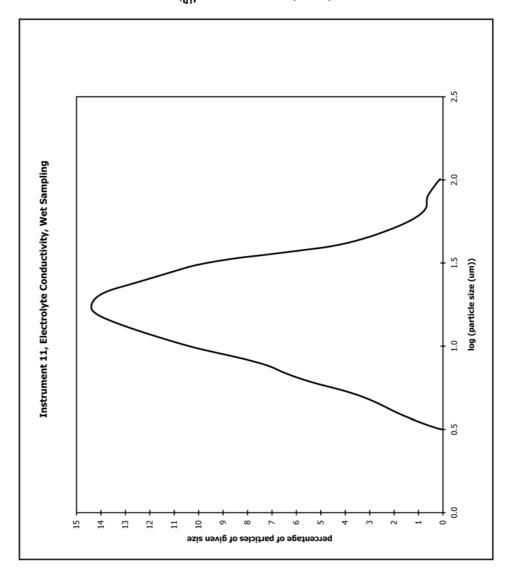


FIG. A1.9 Instrument 9, Laser Scattering, Dry Sampling



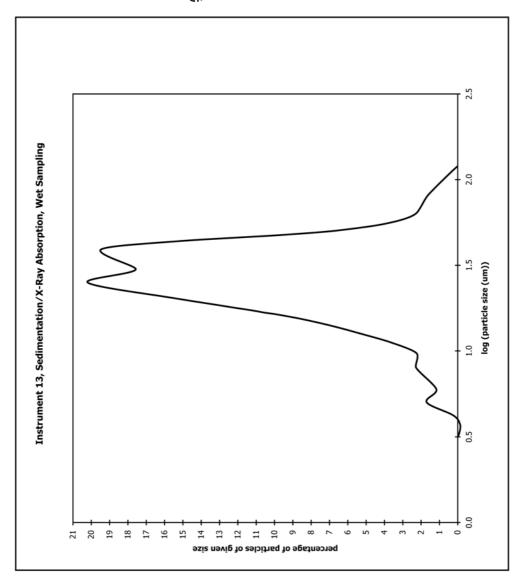
	Percentage of	particles of given size	0.1	0.7	1.1	1.9	3.2	5.3	7.7	10.3	12.8	14.9	14.5	12.0	0.6	4.5	1.4	
10:	Log (size)		0.6021	0.7024	0.8028	0.9031	1.0035	1.1038	1.2041	1.3045	1.4048	1.5051	1.6055	1.7059	1.8062	1.9065	2.0069	
Instrument 10:	Particle	Size (um)	4.0	2.0	6.4	8.0	10.1	12.7	16.0	20.2	25.4	32.0	40.3	50.8	64.0	9.08	101.6	

FIG. A1.10 Instrument 10, Electrolyte Conductivity, Wet Sampling



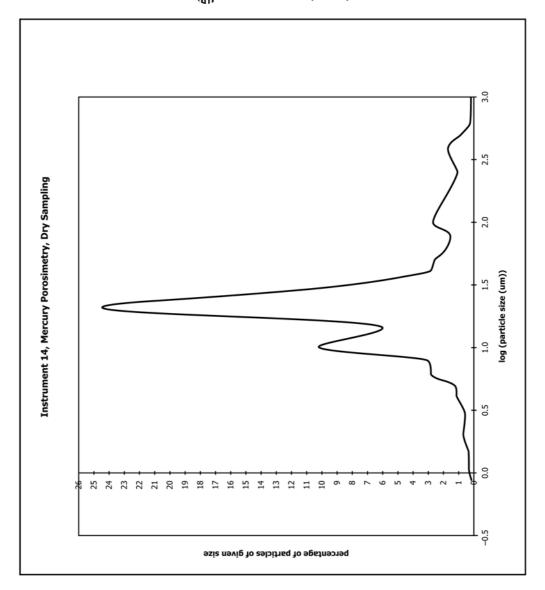
Instrument 11:	11:	
Particle	Log (size)	Percentage of
Size (nm)		particles of given size
3.2	0.5011	0.2
4.0	0.6010	1.9
5.0	0.7016	3.4
6.3	0.8021	5.9
8.0	0.9025	7.6
10.1	1.0026	10.5
12.7	1.1031	12.7
16.0	1.2036	14.3
20.1	1.3038	14.0
25.4	1.4041	11.9
32.0	1.5045	9.5
40.3	1.6049	4.4
50.7	1.7052	2.1
63.9	1.8055	8.0
80.5	1.9058	9.0
101.4	2.0062	0.1

FIG. A1.11 Instrument 11, Electrolyte Conductivity, Wet Sampling



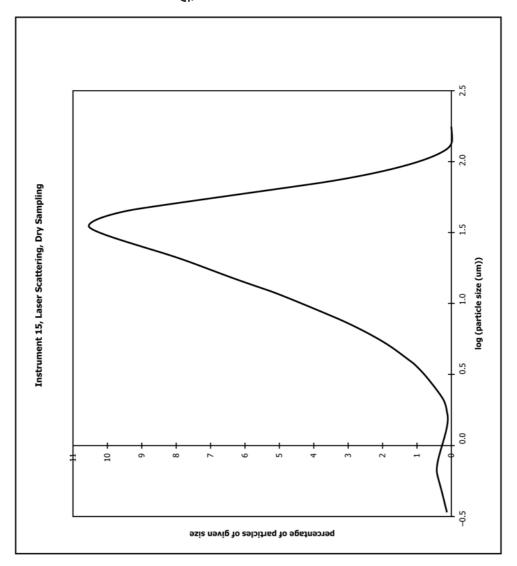
Instrument 13:	13:	
Particle	Log (size)	Percentage of
Size (nm)		particles of given size
3.0	0.4771	0.0
4.0	0.6021	0.0
5.0	0.6990	1.7
0.9	0.7782	1.2
8.0	0.9031	2.3
10.0	1.0000	2.4
15.0	1.1761	8.0
20.0	1.3010	15.1
25.0	1.3979	20.2
30.0	1.4771	17.6
40.0	1.6021	19.3
20.0	1.6990	7.0
0.09	1.7782	2.7
80.0	1.9031	1.7
100.0	2.0000	8.0
120.0	2.0792	0.0

FIG. A1.12 Instrument 13, Sedimentation/X-Ray Absorption, Wet Sampling



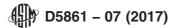
Instrument 14:	14:	
Particle	Log (size)	Percentage of
Size (um)		particles of given size
8.0	6960'0-	0.0
1.0	0.0000	0.3
1.5	0.1761	0.4
2.0	0.3010	0.7
3.0	0.4771	9.0
4.0	0.6021	1.1
5.0	0.6990	1.3
0.9	0.7782	2.8
8.0	0.9031	3.2
10.0	1.0000	10.2
15.0	1.1761	6.4
20.0	1.3010	24.1
25.0	1.3979	18.2
30.0	1.4771	9.7
40.0	1.6021	3.1
50.0	1.6990	5.6
0.09	1.7782	1.9
80.0	1.9031	1.6
100.0	2.0000	2.7
150.0	2.1761	2.0
200.0	2.3010	1.4
250.0	2.3979	1.1
300.0	2.4771	1.4
400.0	2.6021	1.7
500.0	2.6990	6.0
0.009	2.7782	0.3
800.0	2.9031	0.2
1000.0	3.0000	0.2

FIG. A1.13 Instrument 14, Mercury Porosimetry, Dry Sampling



Instrument I Particle	15: Log (size)	Percentage of
(mm)	(25/6)	
Γ	-0.4685	0.1
	-0.2716	0.3
	-0.1871	0.4
8.0	-0.1051	0.4
	-0.0223	0.3
1.2	0.0607	0.2
1.4	0.1430	0.1
1.7	0.2253	0.1
2.0	0.3086	0.2
	0.3918	9.4
3.0	0.4749	0.7
3.6	0.5575	1.0
4.4	0.6405	1.5
5.3	0.7235	1.9
6.4	0.8062	2.6
7.7	0.8890	3.3
9.4	0.9720	4.1
11.4	1.0550	4.9
13.7	1.1380	5.9
16.6	1.2209	8.9
20.1	1.3037	7.7
4	1.3867	8.8
ı.	1.4696	6.6
.7	1.5525	10.5
43.2	1.6354	8.6
52.3	1.7183	7.8
63.3	1.8012	5.3
9.92	1.8841	3.0
92.7	1.9671	1.4
112.2		0.4
135.8	2.1329	0.0
4	2.2158	0.0

FIG. A1.14 Instrument 15, Laser Scattering, Dry Sampling



A2. DATA AS ILLUSTRATED IN Table A2.1

TABLE A2.1 Particle Size Data from Primary Measurement Techniques

Instrument	Method		We	ight Percent of	Particles Retair	ned at Given Si	eve Openings (μm)	
Number	Metriod	<20 μm	20μ m	30 µm	38 µm	45 µm	63 µm	75 µm	90 µm
16	Sieve analysis (dry)	30.1	21.6	29.7		16.5	1.7		0.4
		29.4	21.7	29.9		15.6	3.0		0.4
		31.0	23.0	27.6		15.1	2.9		0.4
17	Sieve analysis (dry)				26.7	14.7		Trace	
					28.3	14.7		Trace	
					27.2	14.4		Trace	

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